Scopus Search Sources Alerts Lists Help SciVal 7 Register Login Author details Receive emails when this author publishes new articles Follow this Author Canavero, Flavio G. About Scopus Author Identifier | View potential author matches Politecnico di Torino, Department of Electronics Other name formats: Canavero, Flavio G. Get citation alerts Canavero, Flavio Canavero, F. G. View More and Telecommunications, Torino, Italy Author ID: 8934782500 Request author detail corrections Documents: 222 Analyze author output Export profile to SciVal Citations: 1567 total citations by 1119 documents h-index: 19 View h-graph Co-authors: 150 (maximum 150 co-authors can be displayed) Subject area: Engineering, Physics and Astronomy View More 222 Documents | Cited by 1119 documents | 150 co-authors 222 documents View all in search results format Sort on: Date Cited by ... Documents Citations **Author History** Simplified topology for integrated circuit buffer El Valid Diouf, C. 2017 IET Circuits, Devices 0 Publication range: 1980 - Present behavioural models Telescu, M., Stievano, and Systems I.S., Tanguy, N., Canavero, F.G. References: 1415 Source history: Find it 6 NTU IEEE Transactions on Circuits and Systems II: Express B View at Publisher Steady-State Analysis of Switching Converters via Frequency-Domain Circuit Equivalents Trinchero, R., Manfredi, P., Stievano, IEEE Transactions on Circuits and Systems II: 2013 17th IEEE Workshop on Signal and Power Integrity 2013 I.S., Canavero, F.G. Express Briefs Proceedings of 7th Electronics Packaging Technology Conference, EPTC 2005 Find it 6 NTU View at Publisher Show Related Affiliations Application of Taylor models to the worst-case analysis of stripline interconnects Manfredi, P., Trinchero, 2016 R., Canavero, F.G., 2016 IEEE 20th Workshop on Signal and Power Integrity, SPI 2016 - Proceedings Stievano, I.S. View at Publisher Find it 🥝 NTU Diouf, C., Telescu, M., Tanguy, N., Stievano, Robust nonlinear models for CMOS buffers 2016 2016 IEEE 20th 0 Workshop on Signal and I.S., Canavero, F.G. Power Integrity, SPI 2016 - Proceedings Find it 6 NTU View at Publisher EMI Prediction of Switching Converters Trinchero, R., 2015 IEEE Transactions on 0 Stievano, I.S. Electromagnetic Canavero, F.G. Compatibility Find it 6 NTU View at Publisher Ding, T., Trinchero, R., Manfredi, P., Stievano, How Affine Arithmetic Helps Beat Uncertainties in 2015 IEEE Circuits and 3 Electrical Systems Systems Magazine I.S., Canavero, F.G. Find it 🧐 NTU View at Publisher Uncertainty analysis in system-level vulnerability Mao, C., Canavero, F. 2015 IEEE International 0 assessment for IEMI Symposium on Electromagnetic Compatibility Find it 6 NTU View at Publisher 2015 IEEE International EMI modeling of switching circuits via augmented 0 Symposium on Electromagnetic Compatibility equivalents and measured data Stievano, I.S. Canavero, F.G. View at Publisher Find it 6 NTU Generalized Decoupled Polynomial Chaos for Nonlinear Manfredi, P., Vande IEEE Microwave and 6

Wireless Components

Letters

Ginste, D., De Zutter,

D., Canavero, F.G.

Circuits with Many Random Parameters

Find it 🥱 NTU

View at Publisher

	upled Polynomial Chaos for Nonlinear Random Parameters	Manfredi, P., Vande Ginste, D., De Zutter, D., Canavero, F. G.	2015	IEEE Microwave and Wireless Components Letters	5
	Find it 6 NTU			Article in Press	
View at Publisher	Modeling for Noise Susceptibility	Fantana M	2015	IEEE Transactions on	0
	nunication Networks	Fontana, M., Canavero, F.G., Perraud, R.	2015	Electromagnetic Compatibility	U
View at Publisher	Find it 6 NTU				
Power-line commu modeling for transp	nication: Channel characterization and portation systems	Degauque, P., Stievano, I., Pignari, S., (), Grassi, F., Cañete, F.J.	2015	IEEE Vehicular Technology Magazine	2
View at Publisher	Find it 6 NTU				
	simulation of microwave devices via based circuit equivalents of nonlinear	Manfredi, P., Canavero, F.G.	2015	IEEE Transactions on Microwave Theory and Techniques	3
View at Publisher	Find it 6 NTU				
EMI Prediction of	Switching Converters	Trinchero, R., Stievano, I. S., Canavero, F. G.	2015	IEEE Transactions on Electromagnetic Compatibility	0
				Article in Press	
View at Publisher	Find it 6 NTU				
	Simulation of Microwave Devices Via -Based Circuit Equivalents of eents	Manfredi, P., Canavero, F. G.	2015	IEEE Transactions on Microwave Theory and Techniques	4
				Article in Press	
View at Publisher	Find it 6 NTU	Cua I Via V 7	2015	IEEE Transactions on	2
	tive solution of electromagnetic pulse onductor transmission lines	Guo, J., Xie, YZ., Canavero, F.G.	2015	Electromagnetic Compatibility	2
View at Publisher	Find it 6 NTU				
	Modeling for Noise Susceptibility nunication Networks	Fontana, M., Canavero, F. G., Perraud, R.	2015	IEEE Transactions on Electromagnetic Compatibility	0
				Article in Press	
View at Publisher	Find it 6 NTU				
Efficient statistical extraction of the per-unit-length capacitance and inductance matrices of cables with random parameters		Manfredi, P., Canavero, F.G.	2015	Advanced Electromagnetics	0
View at Dublishs	Find it 6 NTU			Open Access	
	ative Solution of Electromagnetic Pulse Conductor Transmission Lines	Guo, J., Xie, Y., Canavero, F. G.	2014	IEEE Transactions on Electromagnetic Compatibility	0
				Article in Press	
View at Publisher	Find it 6 NTU				
representation and	ysis of the distributed analytical I iterative technique (DARIT-Field) for o multiconductor transmission lines	Guo, J., Xie, YZ., Li, KJ., Canavero, F.	2014	IEEE Transactions on Electromagnetic Compatibility	5
View at Publisher	Find it 6 NTU				
Display: 20 🔻	results per page			Page 1	Т

Top of page

The data displayed above is compiled exclusively from articles published in the Scopus database. To request corrections to any inaccuracies or provide any further feedback, please contact us (registration required). The data displayed above is subject to the privacy conditions contained in the privacy policy.

Scopus API
Privacy matters

Terms and conditions Privacy policy
Copyright © 2017 Elsevier B.V. All rights reserved. Scopus® is a registered trademark of Elsevier B.V.
Cookies are set by this site. To decline them or learn more, visit our Cookies page.